

“Interfacial dielectric layer as an origin of polarization fatigue in ferroelectric capacitors”.
Do MT, Gauquelin N, Nguyen MD, Wang J, Verbeeck J, Blom F, Koster G, Houwman EP,
Rijnders G, Scientific Reports **10**, 7310 (2020). <http://doi.org/10.1038/s41598-020-64451-0>